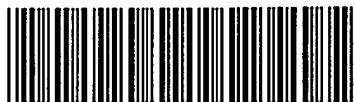


Search Notes**Application/Control No.**

09/549,416

Examiner

CHUONG T. HO

Applicant(s)/Patent under Reexamination

ATTAR ET AL.

Art Unit

2664

SEARCHED

Class	Subclass	Date	Examiner
370	282	07/01/05	CH
370	253		
370	252		
370	389		
370	231		
370	3944		
714	748		
714	749		
370	335		
370	441		
370	442		
370	468		
370	479		
455	458-4		
370	321		
370	349		
370	459		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN EAST WEST IEEE	07/01/05	CH

Search Notes**Application/Control No.**

09/549,416

Examiner

CHUONG T. HO

Applicant(s)/Patent under Reexamination

ATTAR ET AL.

Art Unit

2664

SEARCHED

Class	Subclass	Date	Examiner
370	349	07/01/05	CH
370	394		
370	374		
370	463		
370	474		
370	468v		
370	470v		
370	471v		
370	473v		
370	474v		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
ST N EAST WEST IEEE	07/01/05	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner